



Erratum Erratum: Zhu, Y.; Pal, J. Low-Voltage and High-Reliability RF MEMS Switch with Combined Electrothermal and Electrostatic Actuation. *Micromachines* 2021, *12*, 1237

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The authors would like to update the Figures 3 and 7 to the published paper [1] as follows:

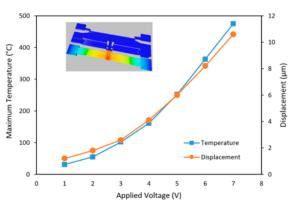


Figure 3. The simulated maximum temperature and displacement of the electrothermal actuator with various applied actuation voltages.

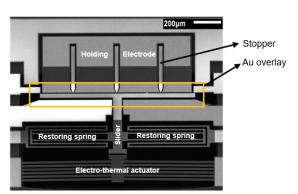


Figure 7. Scanning Electron Microscopy (SEM) photo of the fabricated switch. Au overlay is added to reduce the contact resistance and RF signal loss. Three stoppers ensure no contact and short circuit between movable electrode and holding electrode.

The changes do not affect the scientific results. We apologize for any inconvenience caused to the readers by these errors. The manuscript will be updated with a reference to this Erratum.

Reference

1. Zhu, Y.; Pal, J. Low-Voltage and High-Reliability RF MEMS Switch with Combined Electrothermal and Electrostatic Actuation. *Micromachines* **2021**, *12*, 1237. [CrossRef]



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